

Bayesian active learning for electromagnetic structure design

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Introduction

Design of modern electromagnetic and electronic circuits is a complex task

- Tradeoffs between conflicting design requirements
- Physical effects such as reflection, crosstalk and propagation delays

Computer Aided Design (CAD) is essential

- Systems with high bandwidth and complexity

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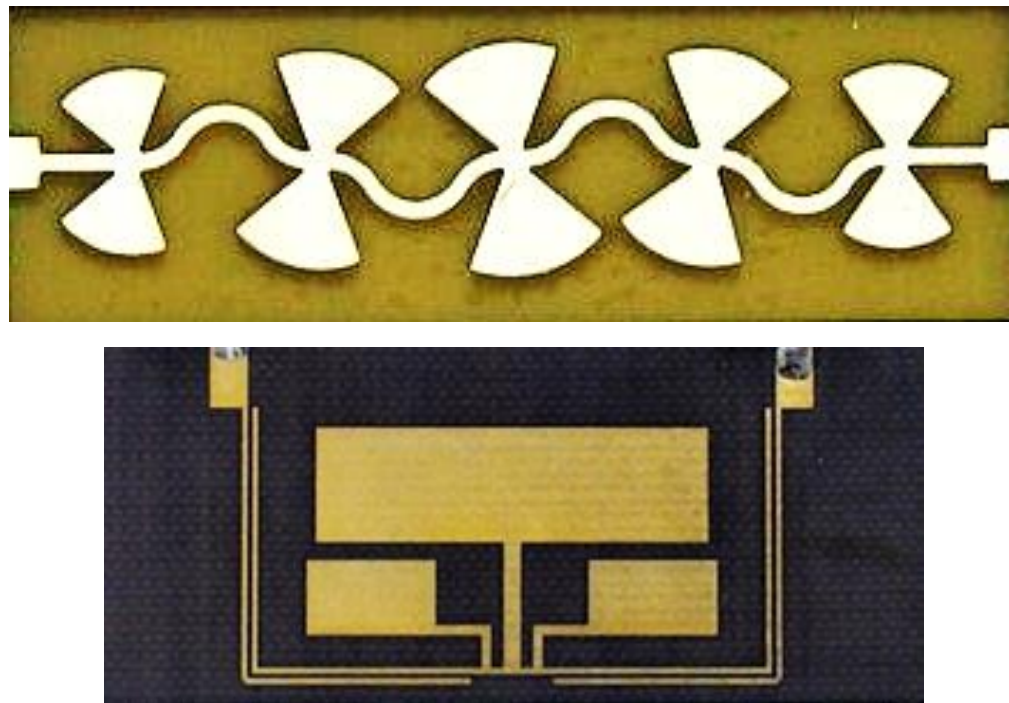
- Systems with high bandwidth and complexity



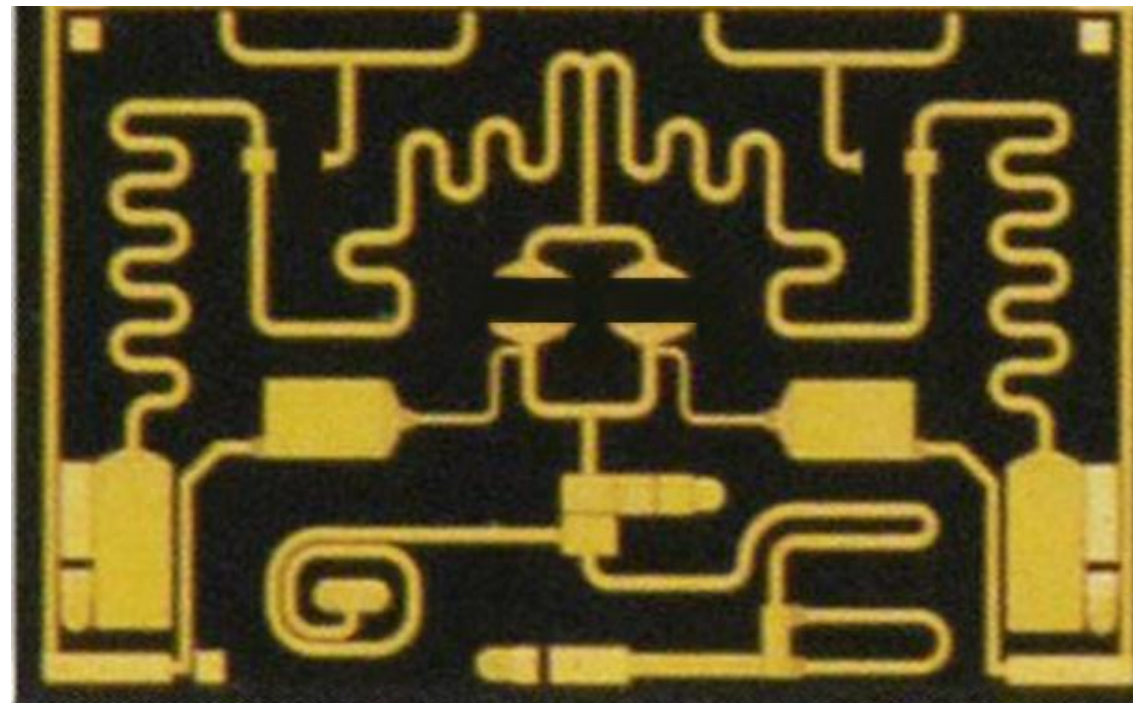
Introduction

Example: RF linear and passive distributed devices

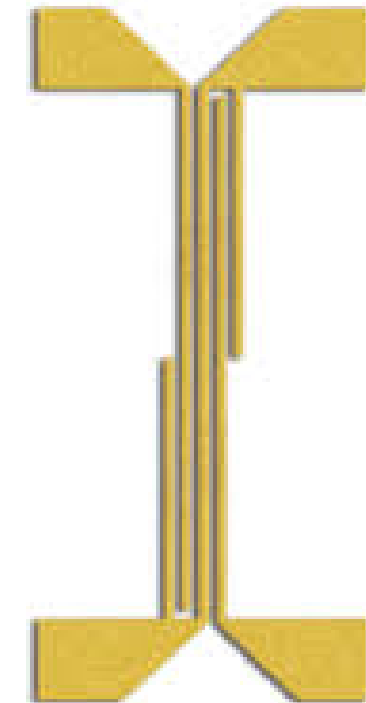
Distributed filters



Matching networks



Couplers

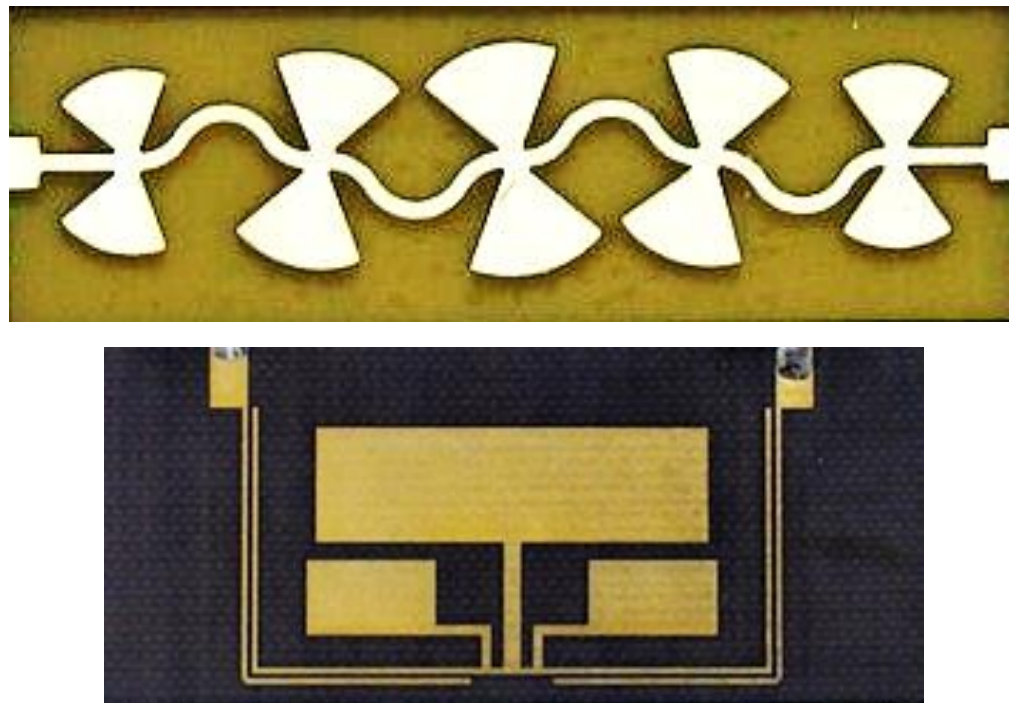


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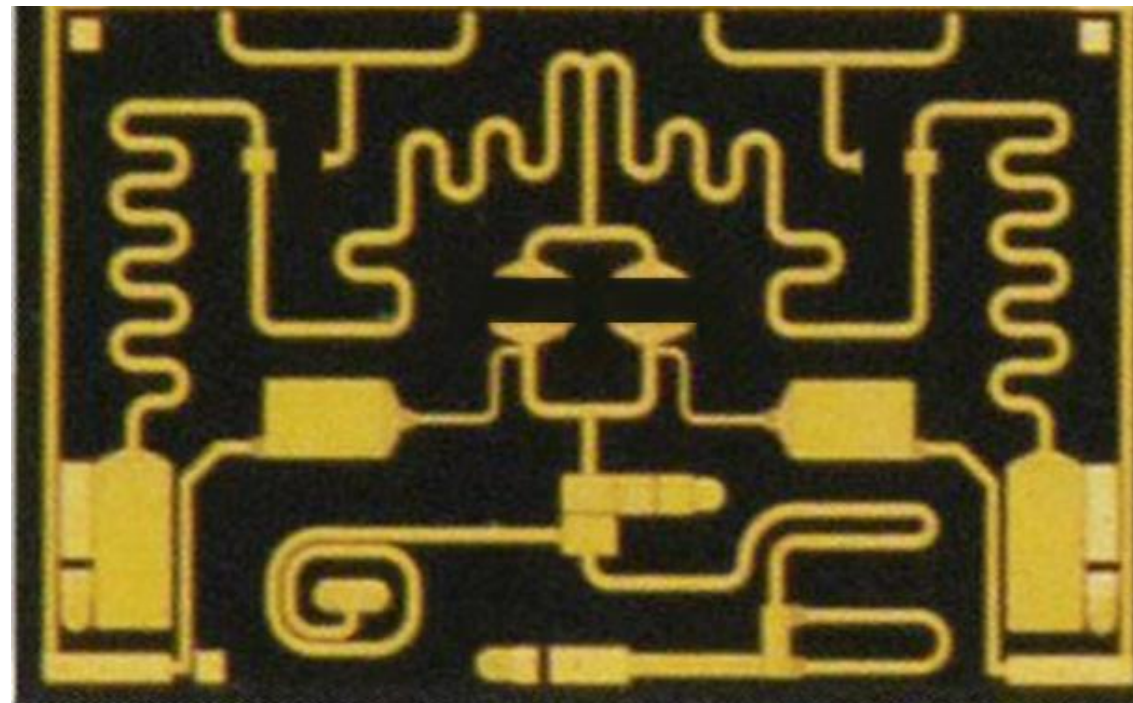
Example: RF linear and passive distributed devices

- Defined by several geometrical or electrical parameters

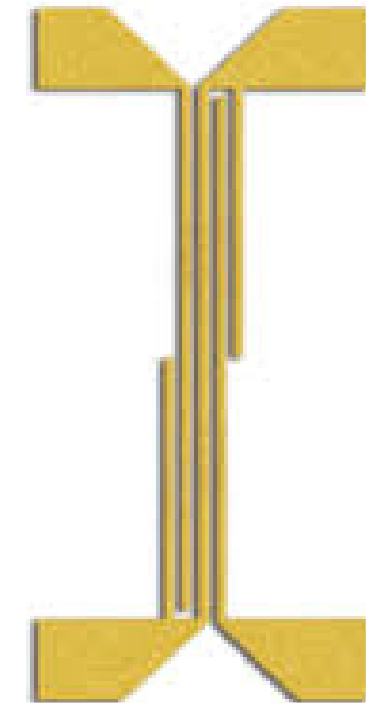
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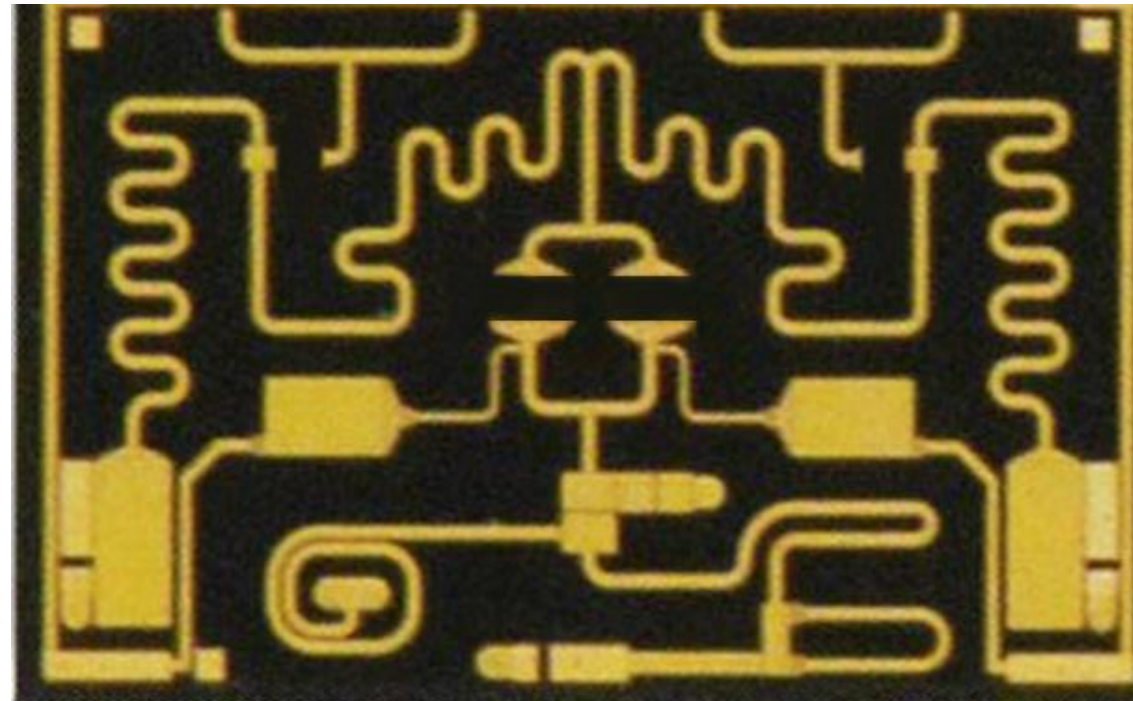
Example: RF linear and passive distributed devices

- Defined by several geometrical or electrical parameters
- For each combination of design parameters
- Time-expensive electromagnetic simulations

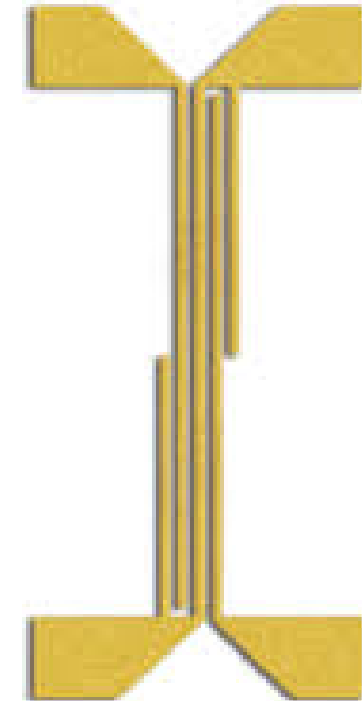
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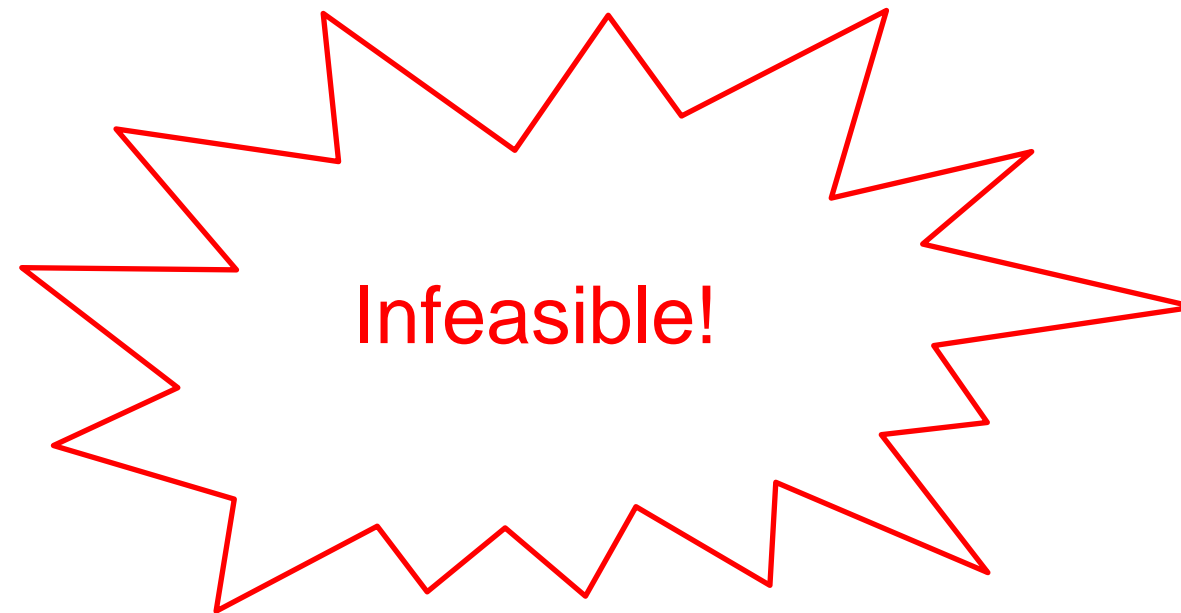
Example: RF linear and passive distributed elements

- The design process requires to perform many simulations
- Design space exploration, optimization, uncertainty quantification

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Introduction

Idea

- Identifying designs satisfying suitable criteria (application-dependent)
- With a limited number of expensive simulations

The desired design solutions form the ***target region***

This can:

1. Reduce the complexity of the design problem
2. Give insight on the system under study

Introduction

This work:

- Introduces a new methodology for target region identification
- Demonstrates its usefulness by design of a low pass filter
- Provides a PCA based bounding box to describe the target region

Outline

- Goal
- Methodology
- Results and discussion
- Conclusion

Goal

Find

$$A := \{x \in \chi \mid a < f(x) < b\}$$

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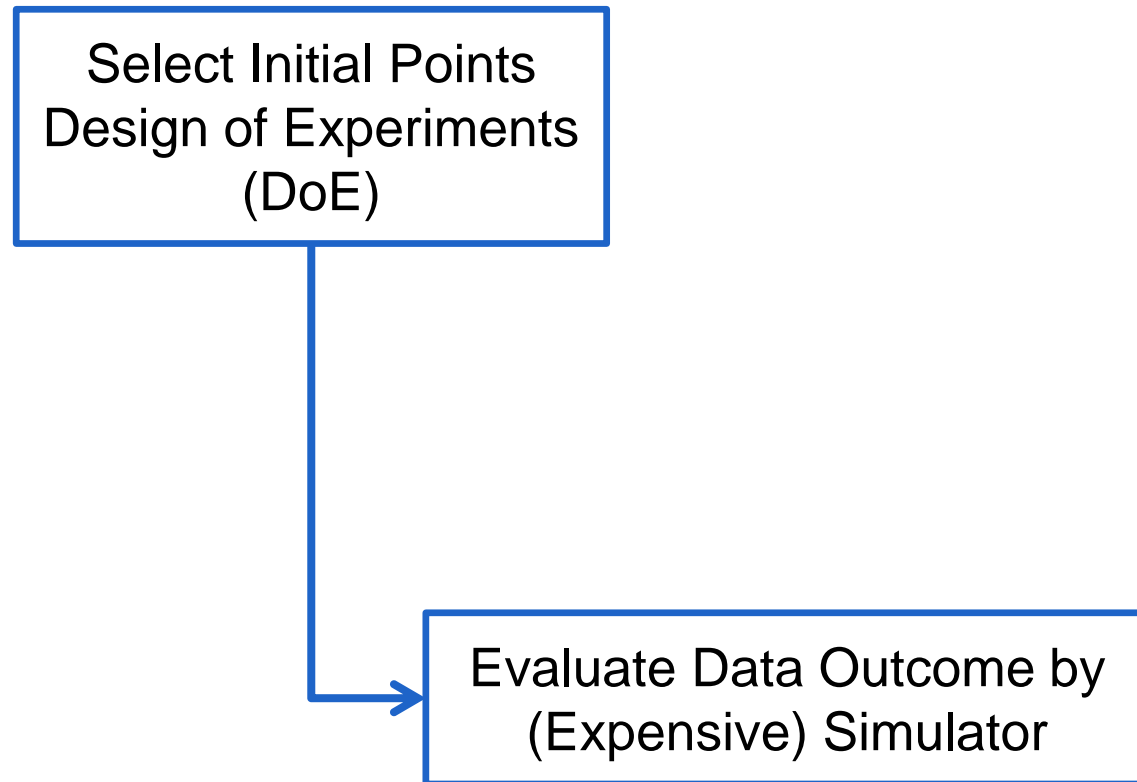
Diagram illustrating the components of the optimization problem:

- Target region**: Points to the set A .
- Design parameters**: Points to the variable x .
- Design space**: Points to the set χ .
- Expensive simulator**: Points to the function f .

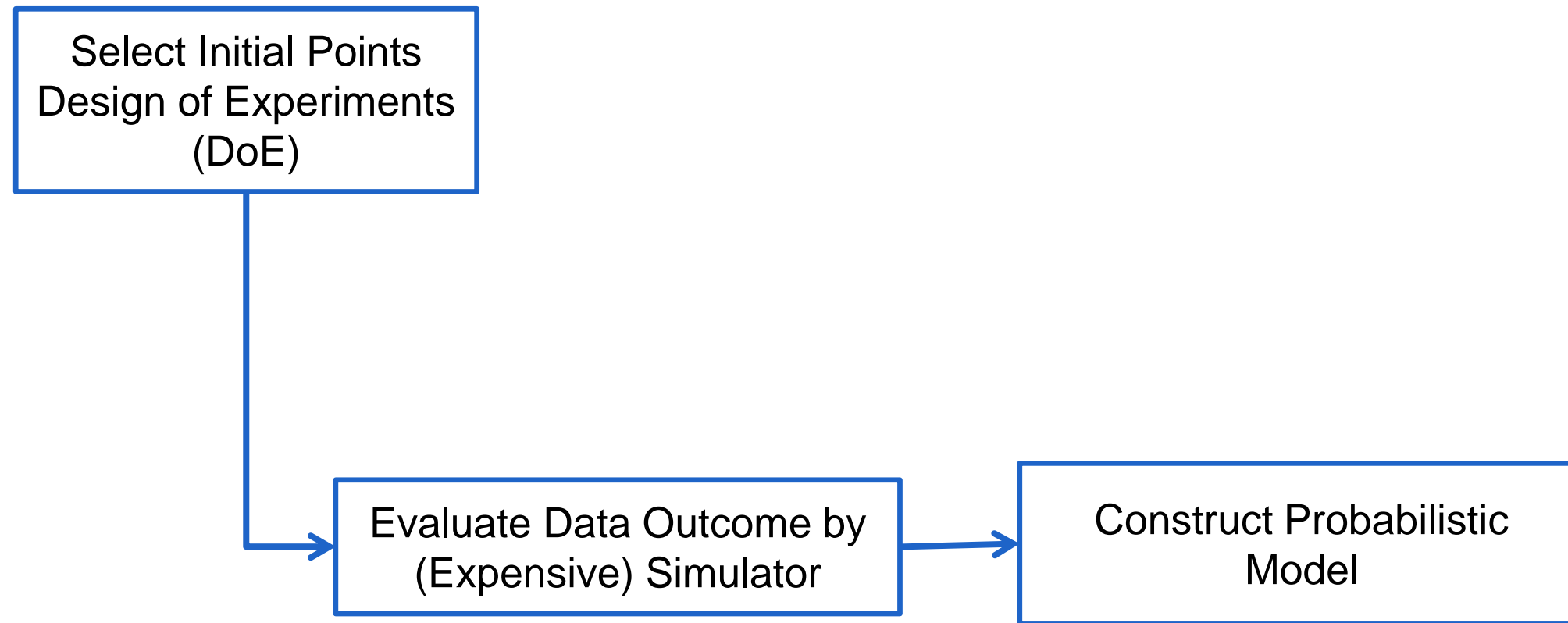
Methodology

Select Initial Points
Design of Experiments
(DoE)

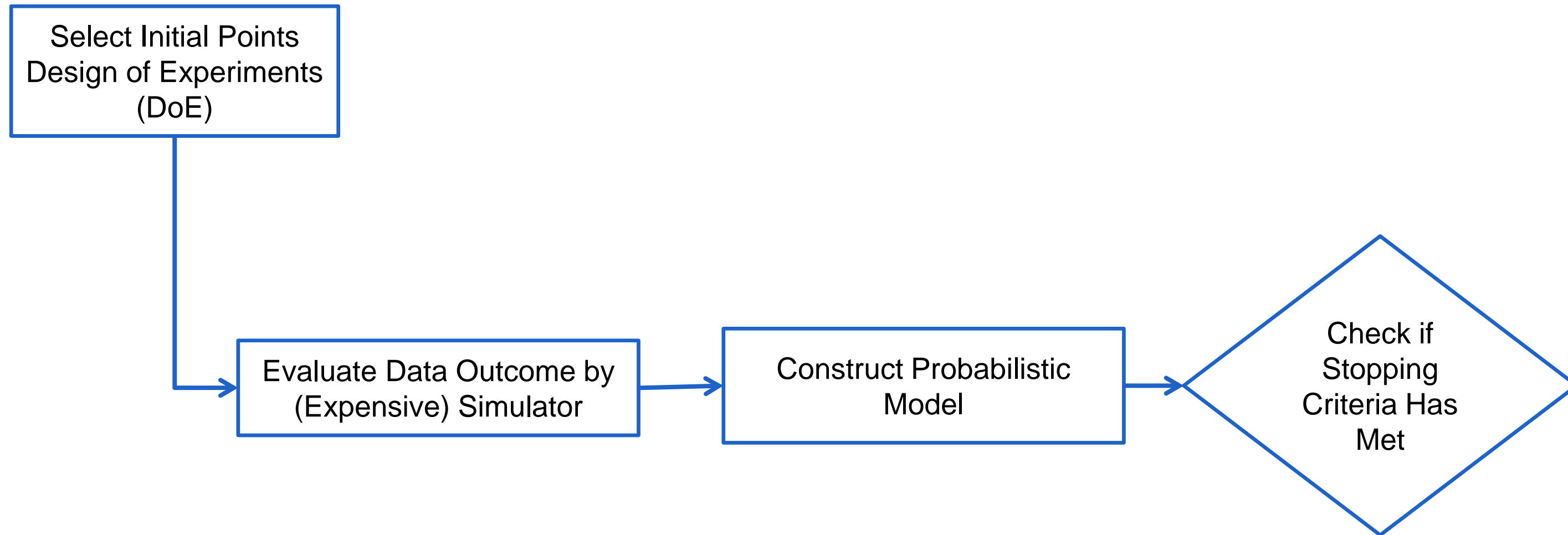
Methodology



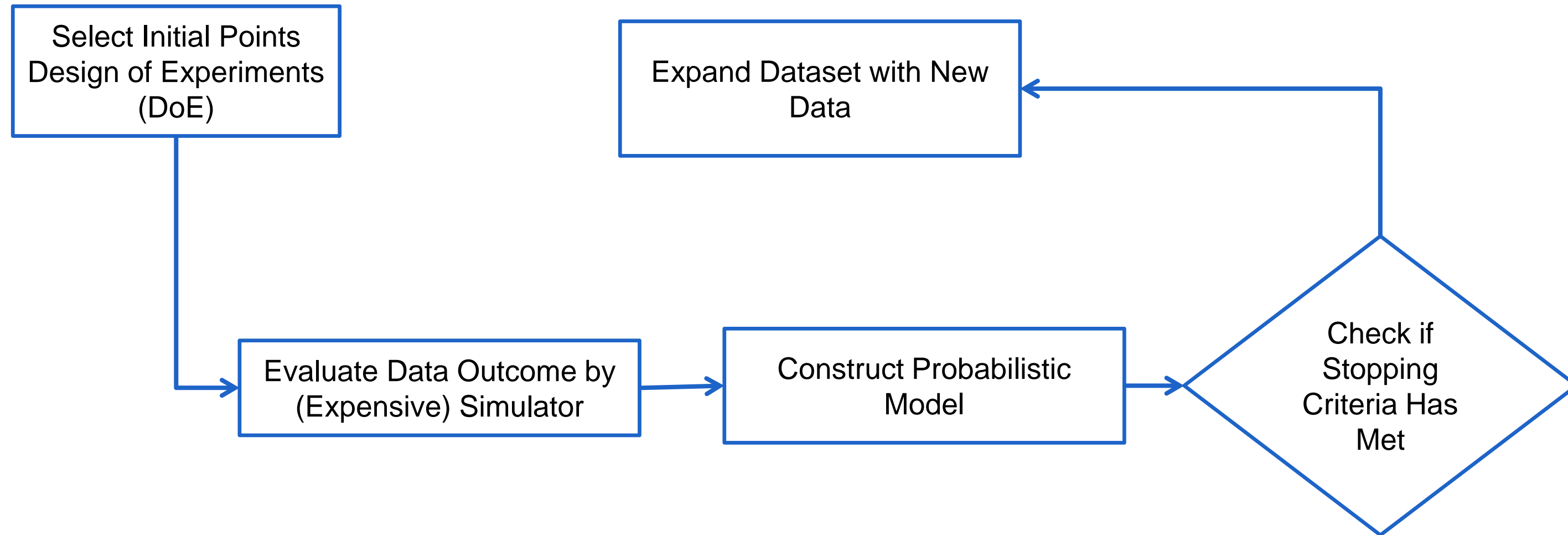
Methodology



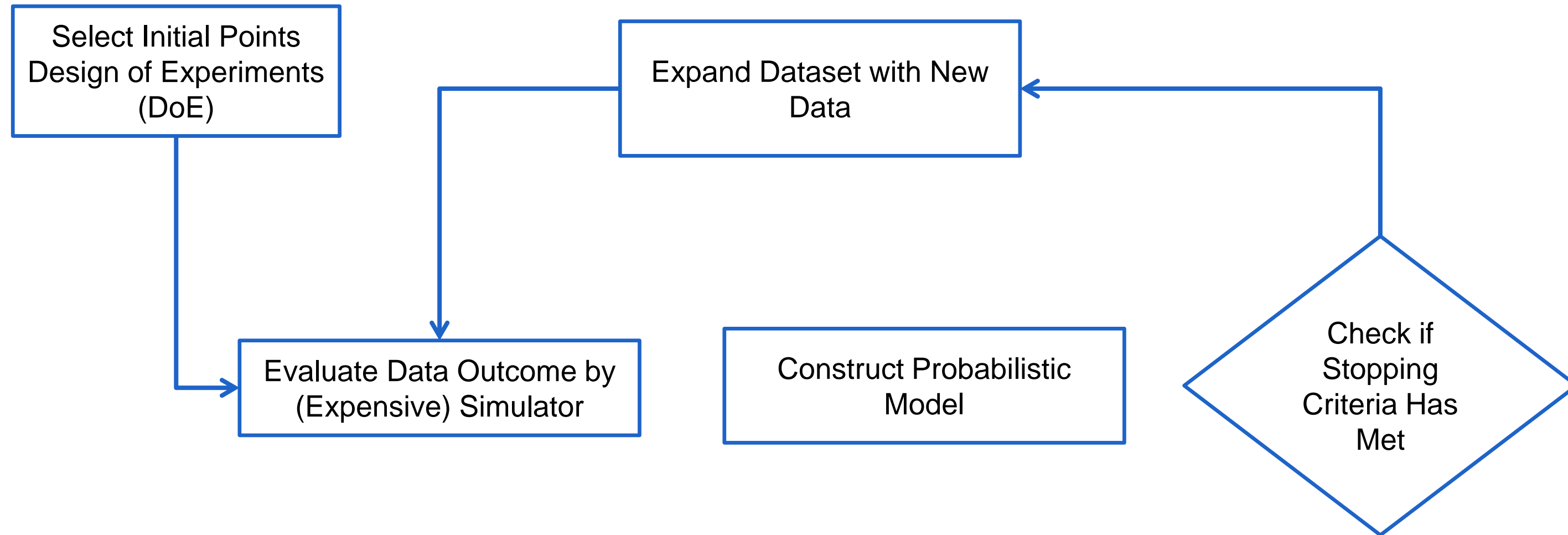
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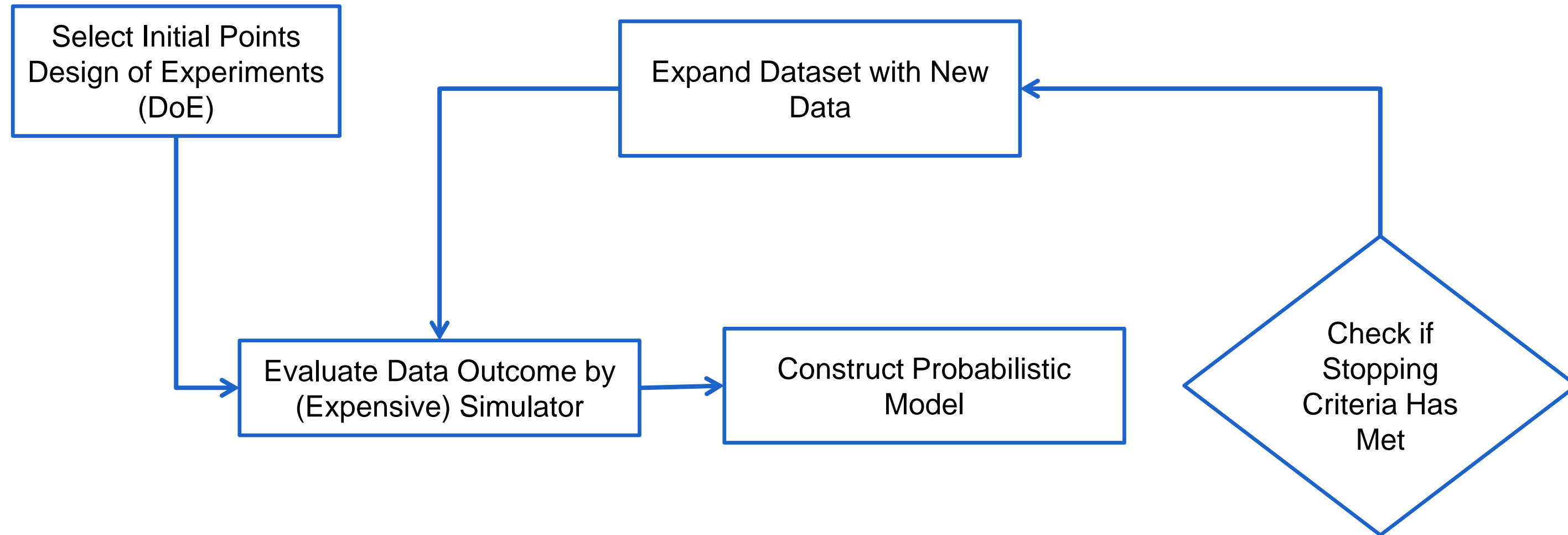
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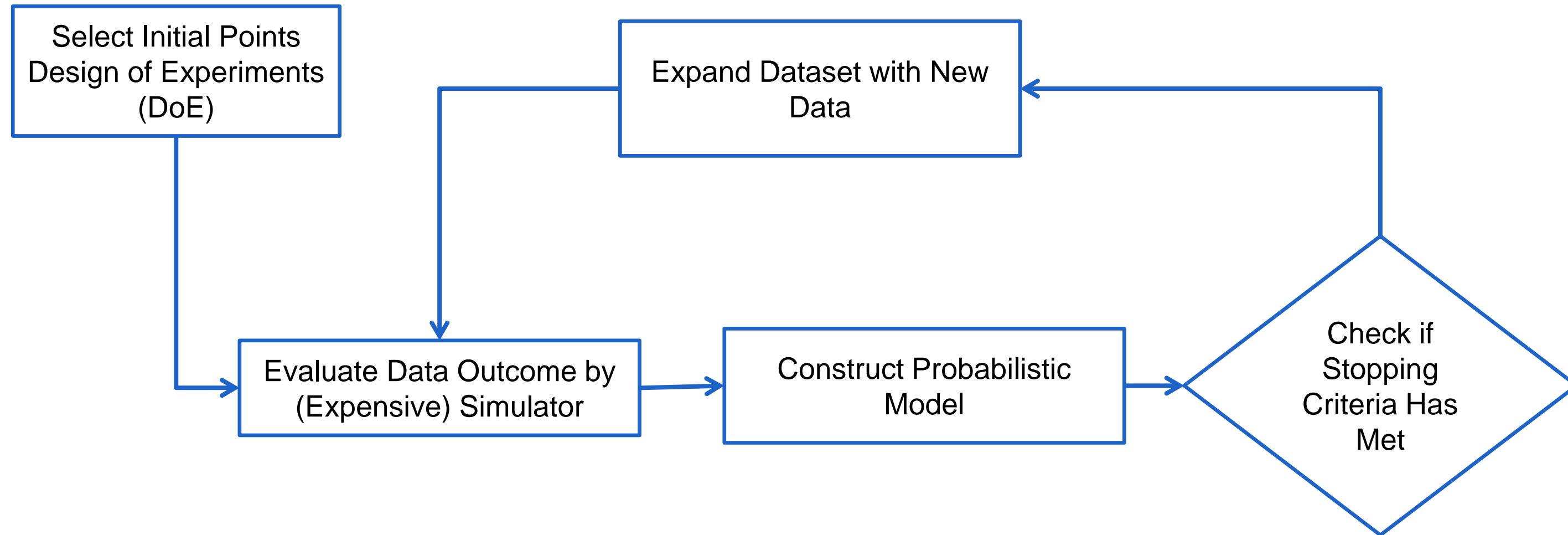
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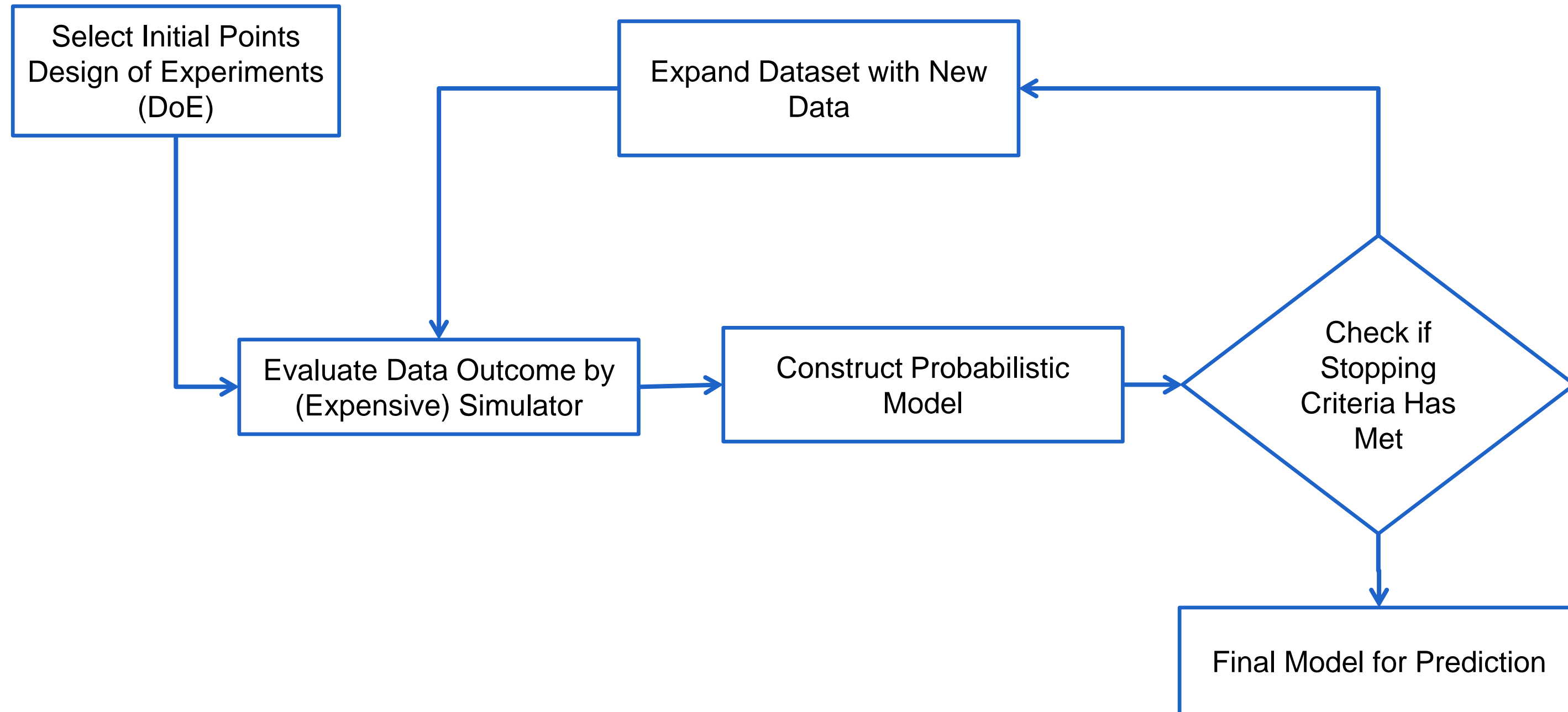
Methodology



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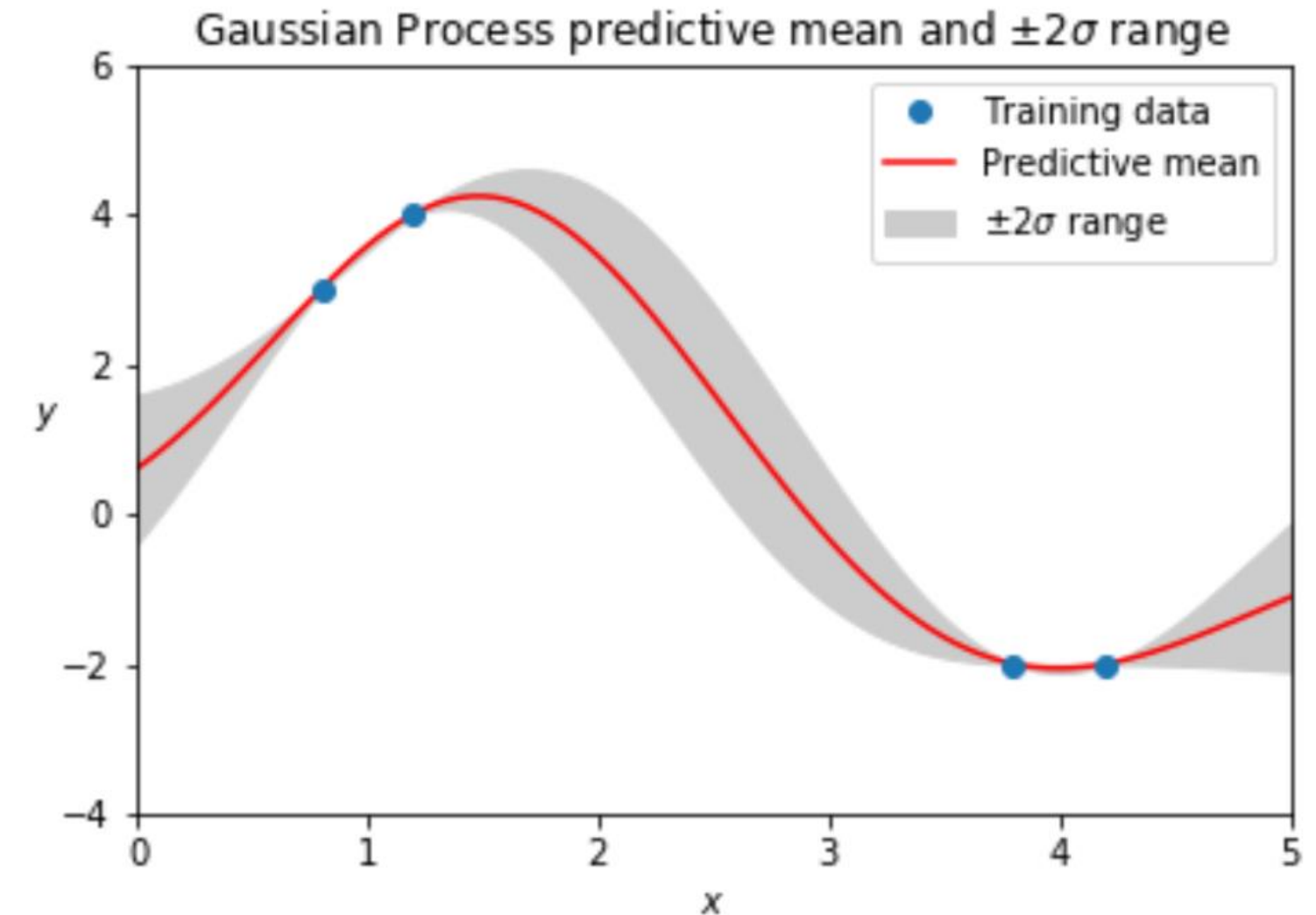
Methodology

A **surrogate model** is a computationally **cheap** probabilistic model to describe the real problem

Gaussian Process [1]

$$\mu(\mathbf{x}_*) = \mathbb{E}(f_* | \mathbf{x}_*, D_n) = \mathbf{k}_{*n}^T (\mathbf{K}_{nn} + \sigma^2 \mathbf{I})^{-1} \mathbf{y}$$

$$\sigma^2(\mathbf{x}_*) = \mathbb{V}[f_* | \mathbf{x}_*, D_n] = \mathbf{K}_{**} - \mathbf{K}_{n*}^T (\mathbf{K}_{nn} + \sigma^2 \mathbf{I})^{-1} \mathbf{K}_{n*}$$



[1] Rasmussen, Carl Edward. "Gaussian processes in machine learning." Summer School on Machine Learning. Springer, Berlin, Heidelberg, 2003.

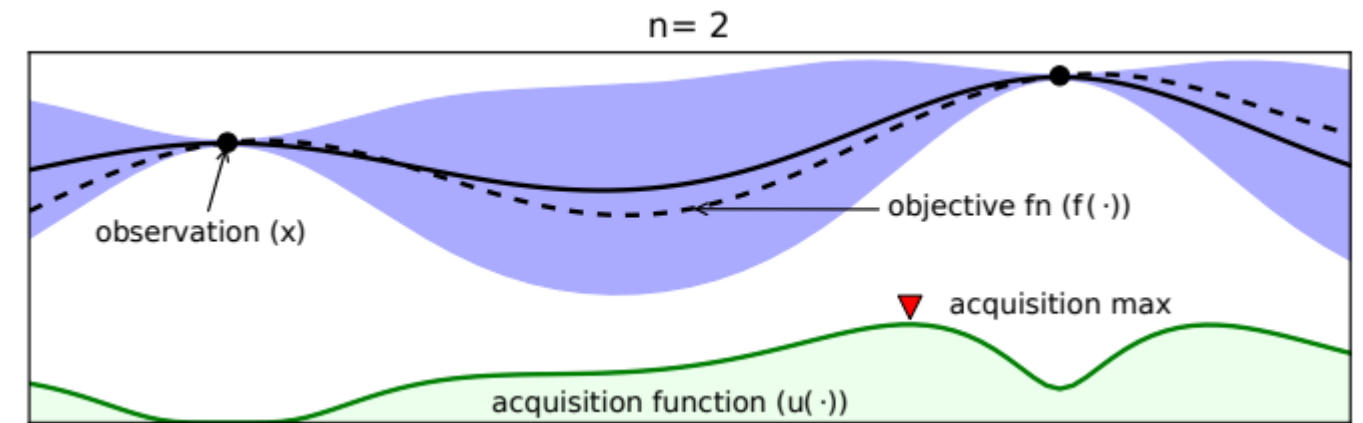
Methodology

$$\alpha(\mathbf{x}) = \mathbb{H}(p(g|D_n)) - \mathbb{E}_{p(f_{\mathbf{x}}|D_n, \mathbf{x})} [\mathbb{H}(p(g|D_n \cup \{\mathbf{x}, f_{\mathbf{x}}\}))]$$

Bayesian Active Learning by Disagreement (BALD) [2]

$$\begin{aligned} & \mathbb{H}(p(f|D_n, \mathbf{x})) - \mathbb{H}(p(f|D_n, \mathbf{x}, b < f < a)) \\ &= \log(\sqrt{2\pi e\sigma^2}Z) + \\ & \frac{1}{2Z} [(\alpha - \mu)\mathcal{N}(\mu|\alpha, \sigma^2) - (\beta - \mu)\mathcal{N}(\mu|\beta, \sigma^2)] \end{aligned}$$

$$Z = \Phi\left[\frac{\beta - \mu(\mathbf{x})}{\sigma}\right] - \Phi\left[\frac{\alpha - \mu(\mathbf{x})}{\sigma}\right]$$



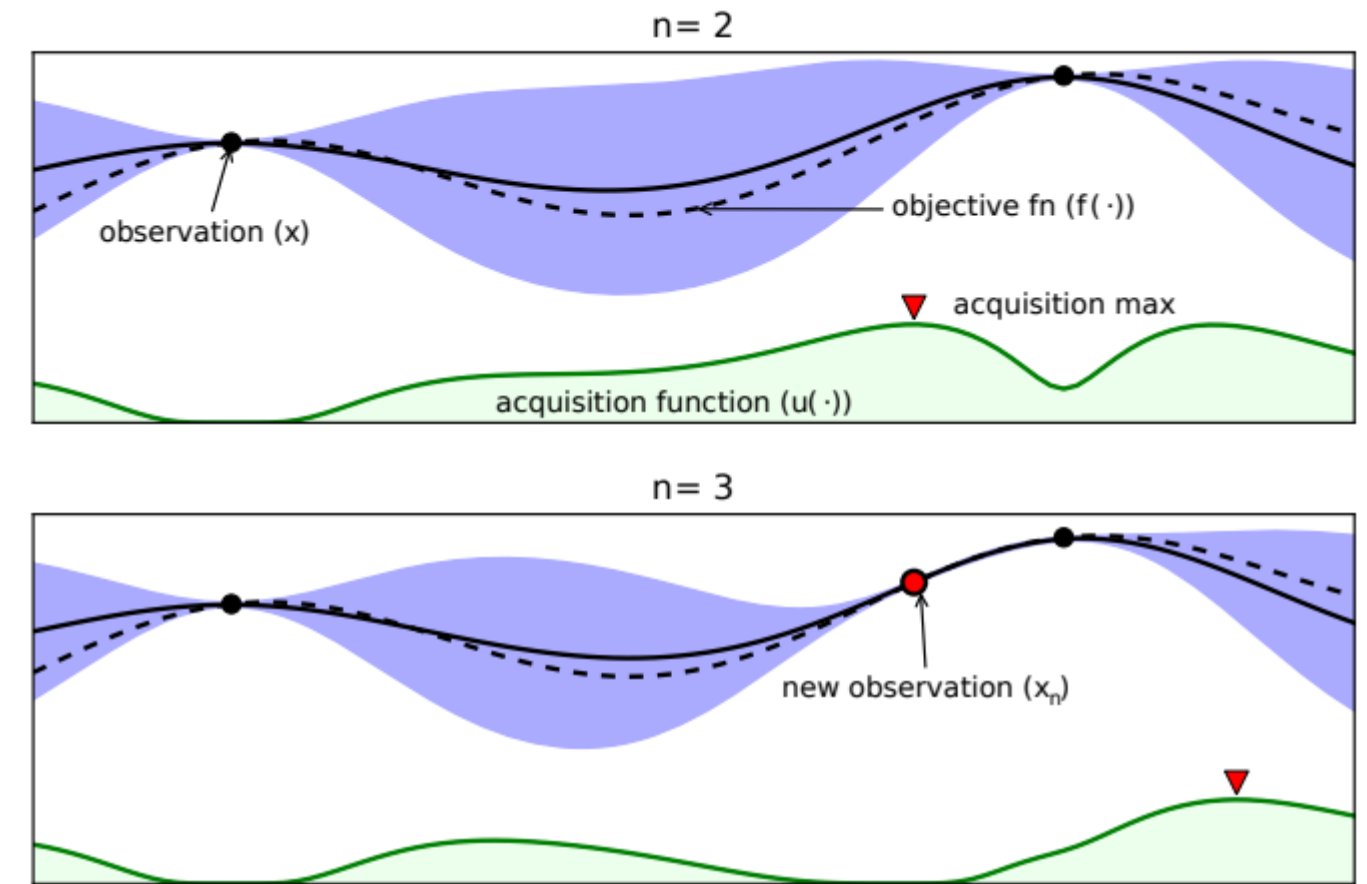
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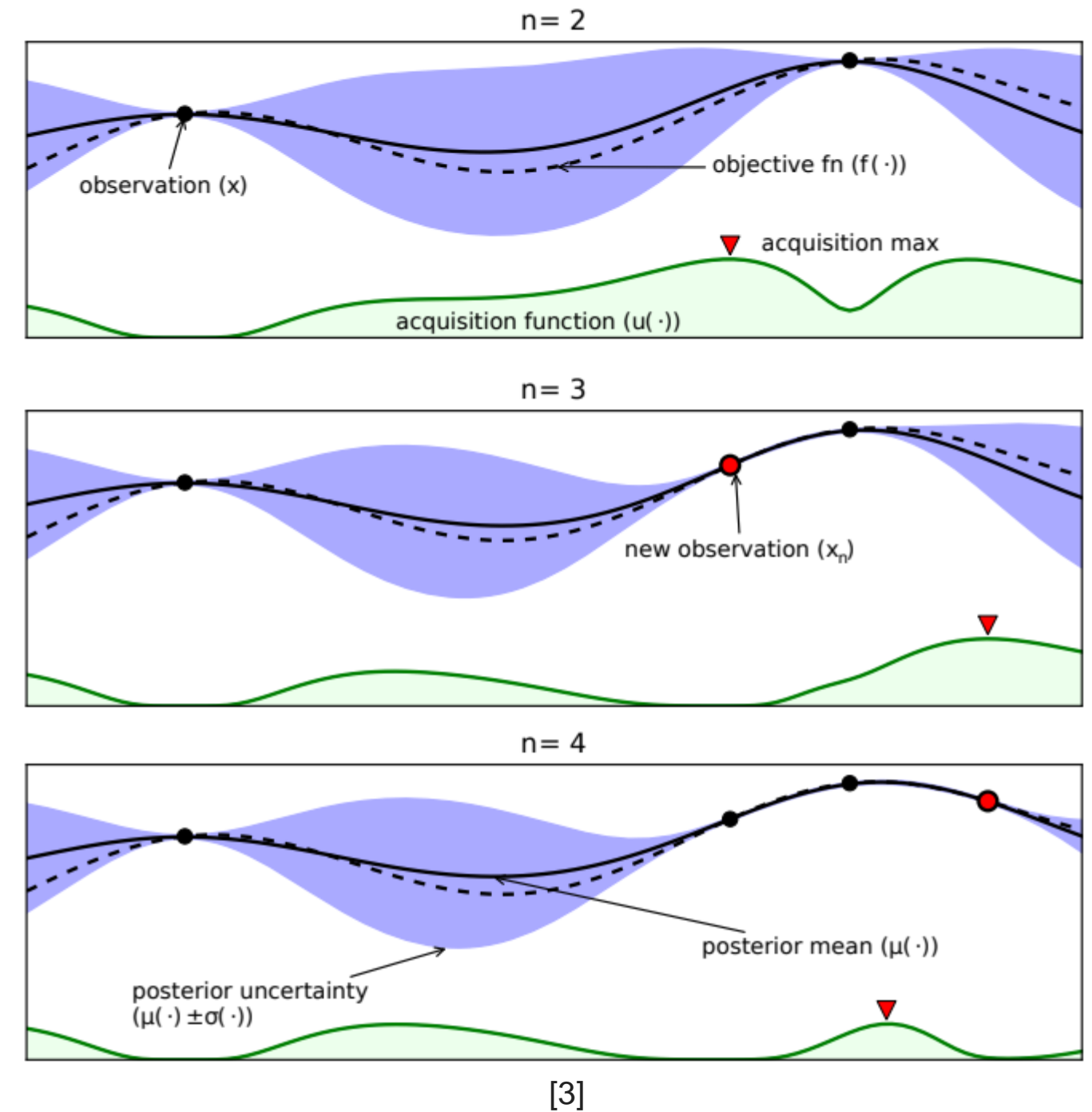
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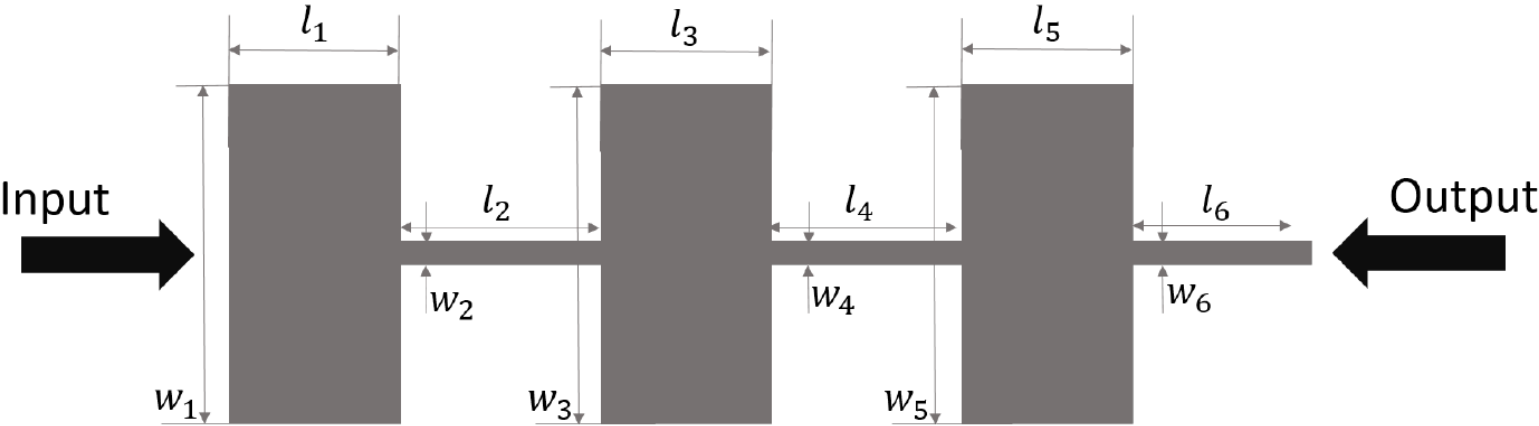
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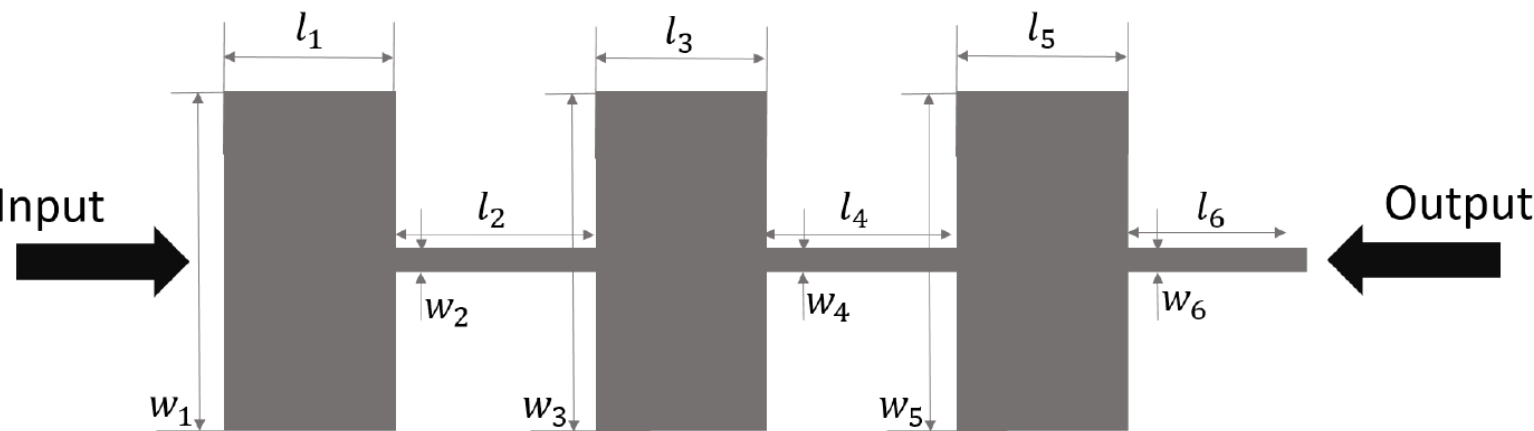


Application: Low Pass Filter Design



Name	Geometry parameter
microstrip lengths	$l_1=2.05$ mm, $l_2=6.63$ mm, $l_3=7.69$ mm, $l_4=9.04$ mm, $l_5=5.63$ mm, $l_6=2.41$ mm
microstrip widths	$w_2 = w_4 = w_6 =0.428$ mm

Application: Low Pass Filter Design



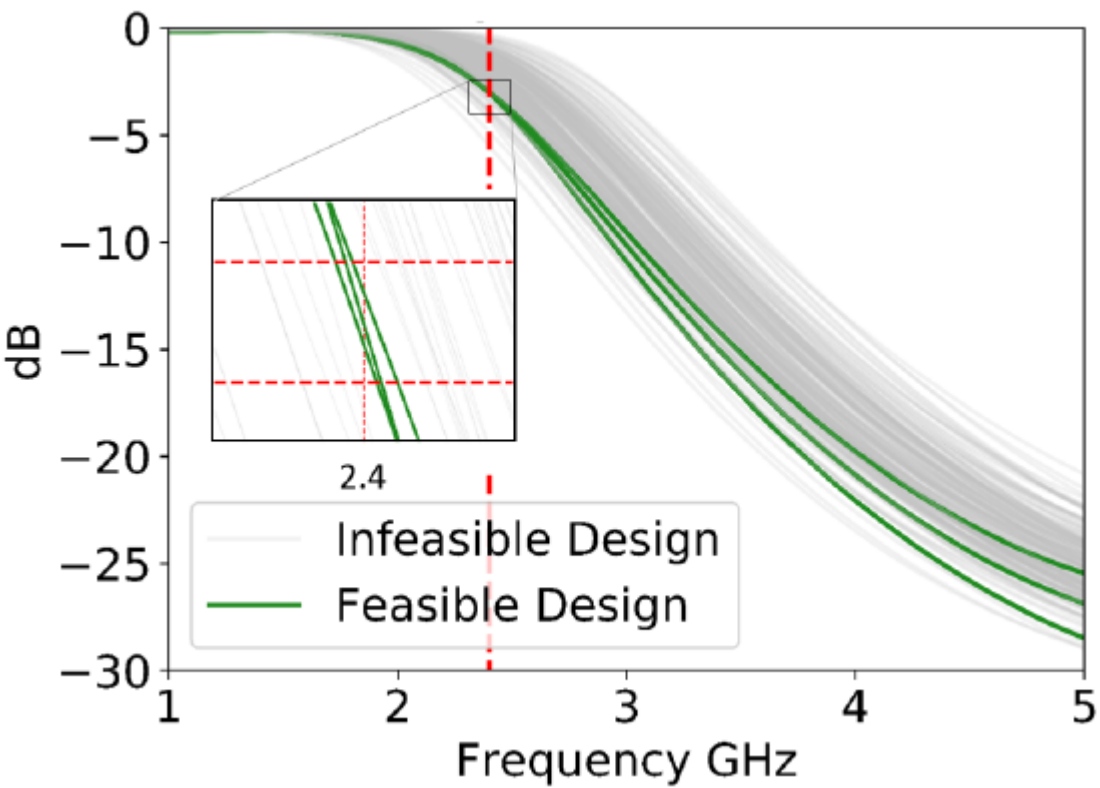
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Design Goal:

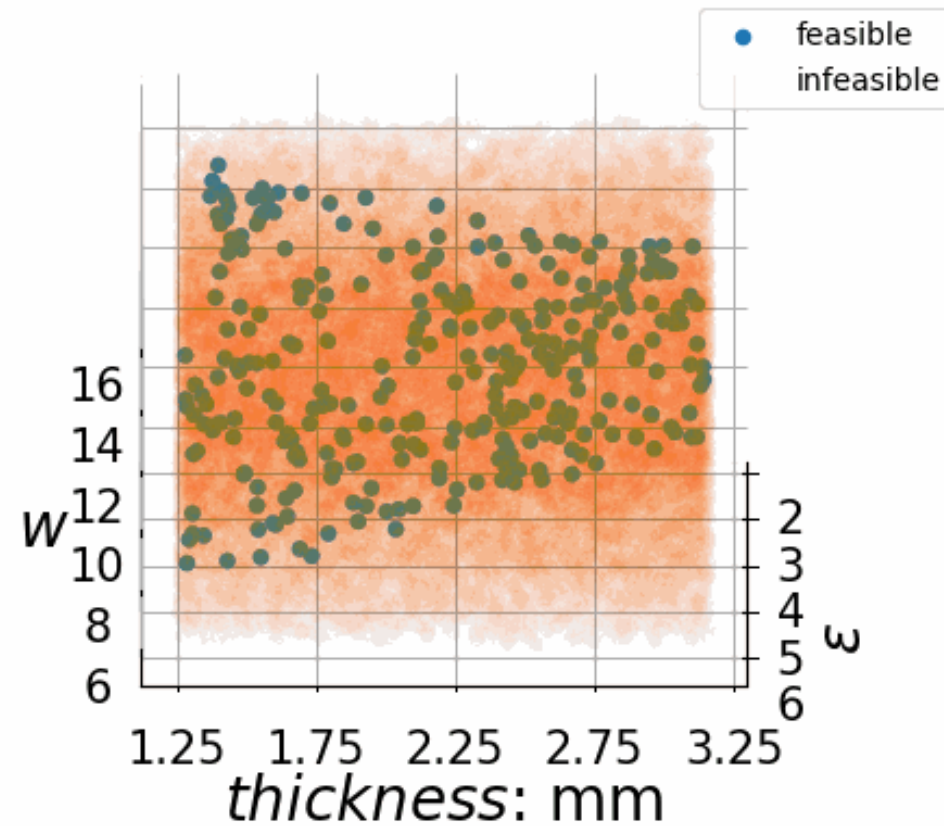
Find $| |S_{12}(f_c, \epsilon, h, w_{1,3,5})|_{\text{dB}} + 3 \text{ dB} | \leq \tau$

subject to

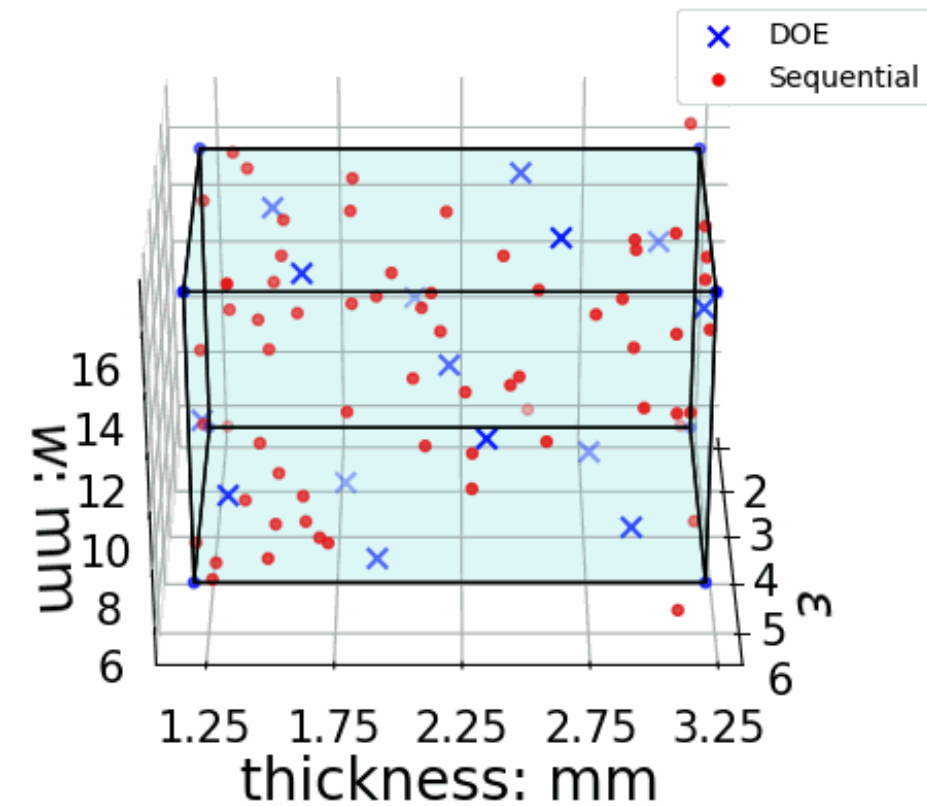
$\epsilon \in [2.1, 6.3]$, $h \in [1.2, 3.2]$ mm, $w_{1,3,5} \in [5.6, 16.9]$ mm



Results and Discussion

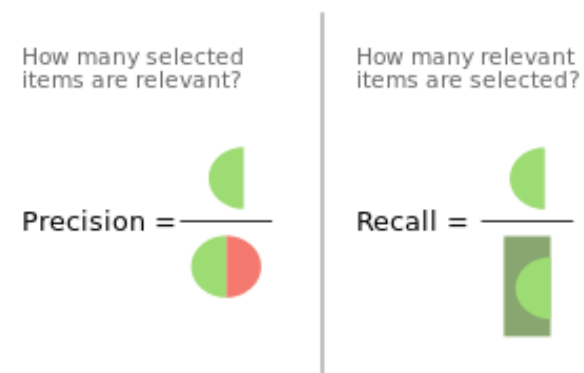
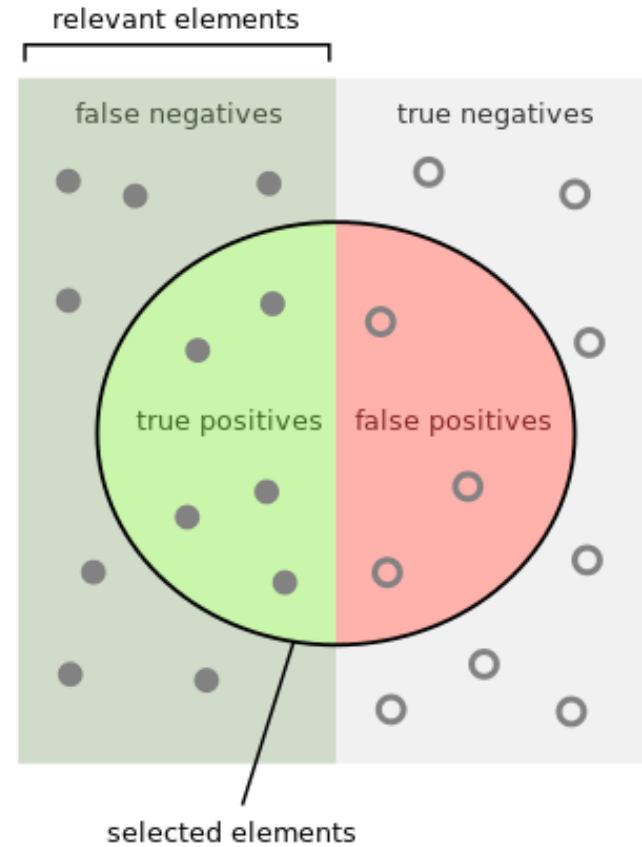


Real target region found by simulation
(**50000** samples generated by Latin Hypercube sampling)

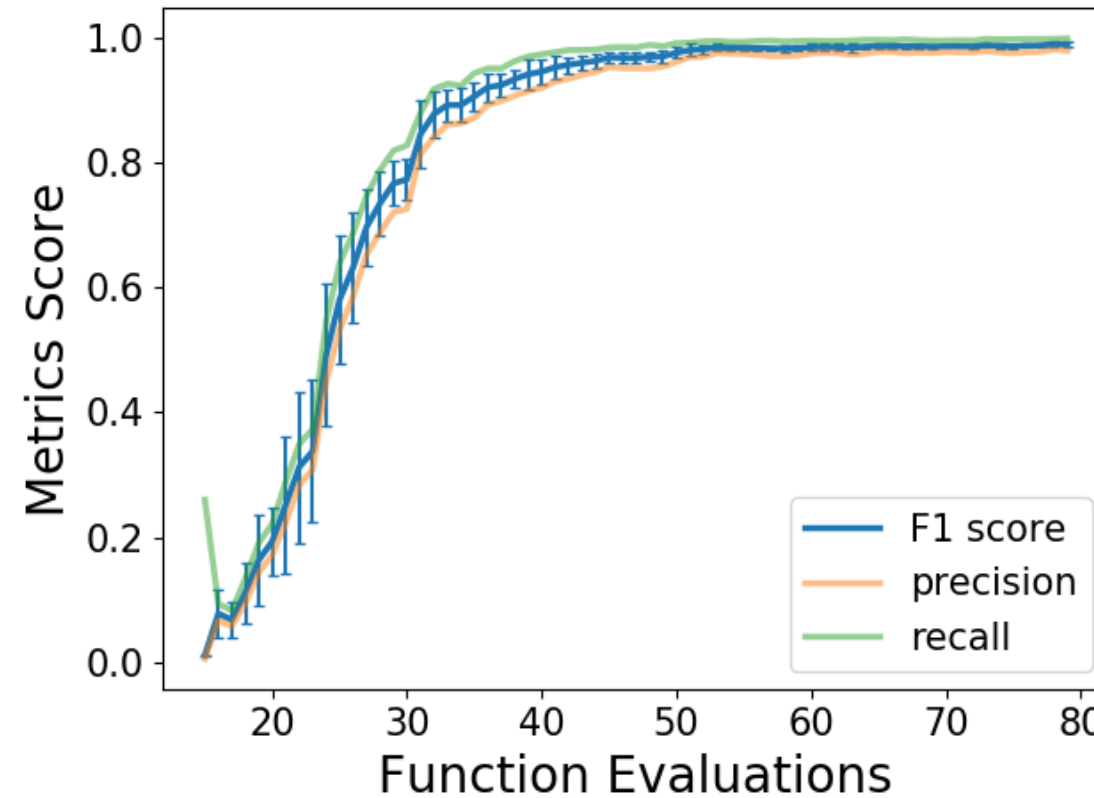


Sequential Active Learning by
Entropy Feasible Search (with only **80** samples)

Results and Discussion



Precision and Recall [4]



Progress Plot of Sequential Sampling
(The experiments is repeated 5 times with error bar shown in the figure)

$$F1 = 2 \cdot \frac{\text{precision} \cdot \text{recall}}{\text{precision} + \text{recall}}$$

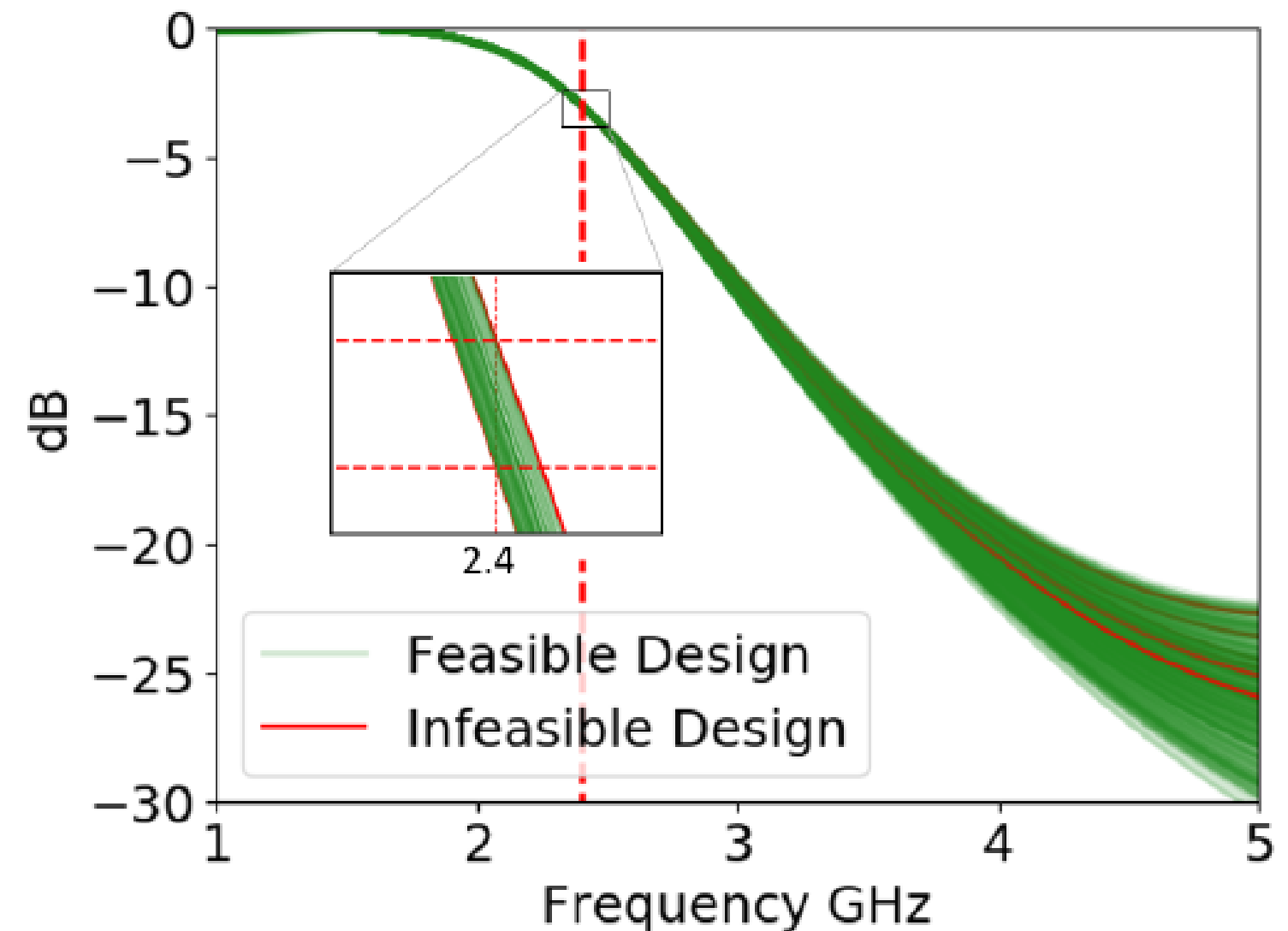


Results and Discussion

We use the **real simulator** to evaluate **323** design configurations predicted feasible by the model.

Only **6** of which are infeasible in reality,

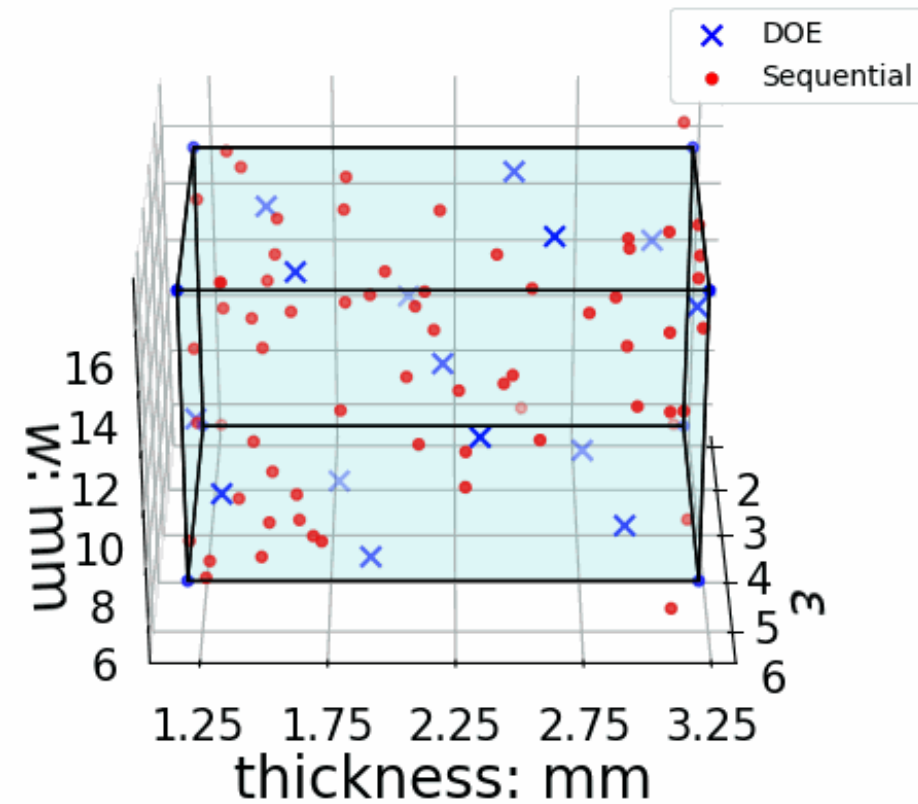
Which means, based on the 323 data points, the ***precision*** of the model is **98.14%**



Results and Discussion

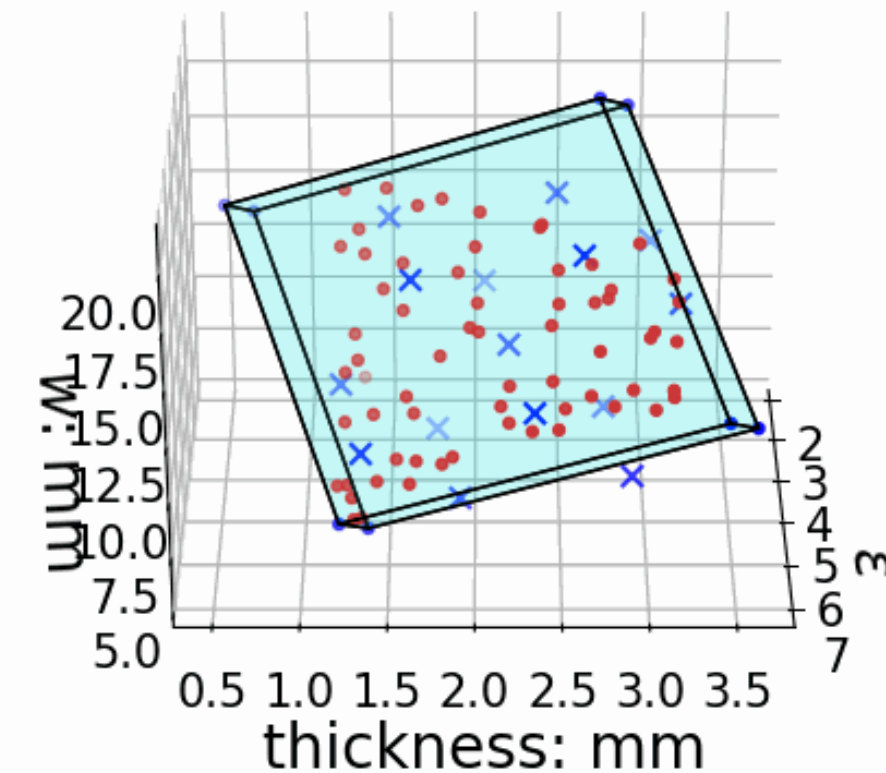
– Feasible region representation

Simple Bounding Box



32% reduction on design space

Principal Component Analysis (PCA)-based approach



85% reduction on design space!

Conclusion

Our approach:

- Provides a way to generate/identify target regions
- Data efficient

Future work:

- Challenging to not violate constraints
- More compact way to describe target region

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